

METHOD FOR ANALYZING IN-LINE QC TEST PARAMETERS

Appl. No.	:	10/604,244	Confirmation No.	1243
Applicant	:	Hung-En Tai, Haw-Jyue Luo		
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Commissioner for Patents
P.O. Box 1450
Alexandria VA 22313-1450

Sir:

In response to the Office action of September 10, 2004, please accept the
5 following remarks beginning on page 2 of this paper.